

**PATENT**

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

<b>APPLICANTS</b>	:	Jong-Cheol Lee, et al.	<b>ATTY DOCKET NO.</b>	:	8836-223JHM/ID12244US
<b>SERIAL NO.</b>	:	10/748,906	<b>EXAMINER</b>	:	Cynthia H. Britt
<b>FILED</b>	:	December 30, 2003	<b>ART UNIT</b>	:	2117
<b>TITLE</b>	:	<i>SEMICONDUCTOR MEMORY DEVICE TESTABLE WITH A SINGLE DATA RATE AND/OR DUAL DATA RATE PATTERN IN A MERGED DATA INPUT/OUTPUT PIN TEST MODE</i>			

**MAIL STOP: AMENDMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**AMENDMENT**

SIR :

In response to the Official Action of December 28, 2007, applicants respectfully request that the above-identified application be amended as follows.

Amendments to the Drawings are set forth on page 2 of this Amendment and include a Replacement Sheet for FIG. 2.

Amendments to the claims are reflected in the Listing of Claims that begins on page 3 of this Amendment.

The Remarks portion begins on page 7 of this Amendment.

Attached to this Amendment is an Exhibit A, in which reference numerals shown in FIG. 3, for example, are inserted by hand.